

Applicant : Keshavarzi et al.
Serial No.: 10/620,829
Filed : July 16, 2003

Attorney's Docket No.:10559-678002

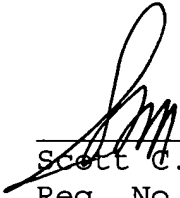
Consideration of the foregoing and enclosures plus the return of a copy of the enclosed form PTO-1449 with the Examiner's initials in the left column per MPEP 609 are earnestly solicited along with an early action on the merits.

Please apply any additional charges or credits to Deposit Account No. 06-1050, referencing attorney docket no. 10559-678002.

Respectfully submitted,

Date: _____

6/17/04



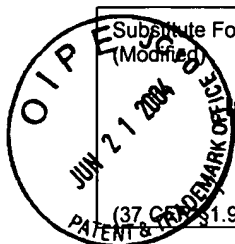
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Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
10559-678002Application No.
10/620,829**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR 1.98(b))

Applicant
Keshavarzi et al.Filing Date
July 16, 2003

Group Art Unit

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,105,078	04/1992	Nochise, et al.			
	AB	5,694,448	12/1997	Morcom			
	AC	6,141,243	10/2000	Aslam, et al.			
	AD	6,388,494	05/2002	Kindt, et al.			
	AE	6,404,269	06/2002	Voldman			
	AF	US-2001-0019285-A1	09/2001	Lin, et al.			
	AG						
	AH						
	AI						
	AJ						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AK							
	AL							
	AM							
	AN							
	AO							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AP	Kelleher et al., IEEE, "Development of the Radiation Sensitivity of PMOS Dosimeters - Développement de la Sensibilité aux Radiations de Dosimètres PMOS", pp. 342-346 (1992)
	AQ	Ma et al., "Ionizing Radiation Effects in Mos Devices and Circuits", John Wiley & Sons, pp. 262, 265-267 (1989)
	AR	Moreno et al., "CMOS Radiation Sensor with Binary Output", IEEE Transactions on Nuclear Science, Vol. 42, No. 3, pp. 174-178, June 1995
	AS	Ray et al., IEEE Transactions on Nuclear Science, "CRRES Dosimetry Results and Comparisons Using the Space Radiation Dosimeter and P-Channel MOS Dosimeters", Vol. 39, No. 6, pp. 1846-1850, December, 1992

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.